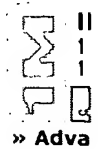


IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**
[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

```
(signal <phrase> (detection
<or> detecting)) <and> (dial
<phrase> (indicator <or>
display <or> meter)) <and>
```


Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:
Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: to
Organize search results by:

 Sort by:

 In: order

 List Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

 Your search matched **0** of **1112315** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

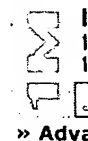
Results:
No documents matched your query.
Print Format
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise®

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype GO[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

```
(internal <phrase> computer  
<phrase> (state <or> status  
<or> condition))
```

Start Search**Clear**

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:**Select publication types:**

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

From year: 1951 to 2002

Organize search results by:

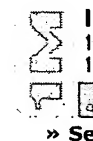
Sort by: Relevance

In: Descending order

List 15 Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1121826** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set.**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.** **Print Format**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**
[Help](#)

1) Enter a single keyword, phrase, or Boolean expression.
 Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)

2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

3) Limit the results by selecting Search Options.

 4) Click Search. See [Search Examples](#)

```
(internal <phrase> computer
<phrase> (state <or> status
<or> condition) <phrase>
(meter <or> indicator))
```

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

 Search operators: <and> <or> <not> <in> [More](#)

 Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:

Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: to

Organize search results by:

Sort by: In: orderList Results per page
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

 Your search matched **0** of **1121826** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

Results:
No documents matched your query.

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

dial <phrase> meter

Start Search**Clear**

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:**Select publication types:**

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

From year: 1951 to 2002

Organize search results by:

Sort by: Relevance

In: Descending order

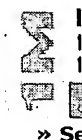
List 15 Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office


>> See:

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **1** of **1121826** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Physically-based geometric constraint resolution***Inui, M.; Tohyama, H.; Miura, M.;*

Assembly and Task Planning, 2001, Proceedings of the IEEE International Symposium on , 28-29 May 2001

Pages:393 - 398

[\[Abstract\]](#) [\[PDF Full-Text \(480 KB\)\]](#) **IEEE CNF**

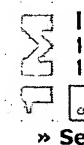
Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

 Your search matched **0** of **1121826** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

Results:
No documents matched your query.
Print Format
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

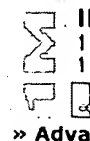
Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**
[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

- 3) Limit the results by selecting Search Options.

- 4) Click Search. See [Search Examples](#)

 computer <phrase> internal
 <phrase> environment

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

 Search operators: <and> <or> <not> <in> [More](#)

 Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)
Search Options:
Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

From year: 1951 to 2002

Organize search results by:

Sort by: Relevance

In: Descending order

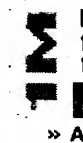
List 15 Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved



Welcome
United States Patent and Trademark Office



[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Try our New Full-text Search Prototype **GO**

Help

To Locate an Author:

1. Enter a last name or select a letter in the alphabet.
2. Once you identify the name, select it to search the database for relevant articles.

1.Options:

» Enter a name to find an author:



Example: Enter Lockett S to obtain a list of authors with the last name Lockett and first name initial S.
OR» Select a letter to browse the author list:

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the
IEEE Enterprise
File Cabinet

A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL

2. Select an author name to search the database for relevant articles:

<u>Davis A.</u>	<u>Davis A. A.</u>	<u>Davis A. B.</u>	<u>Davis A. E.</u>	<u>Davis A</u>
<u>Davis A. J.</u>	<u>Davis A. K.</u>	<u>Davis A. L.</u>	<u>Davis A. M.</u>	<u>Davis A</u>
<u>Davis A. O.</u>	<u>Davis A. P.</u>	<u>Davis A. R.</u>	<u>Davis A. S.</u>	<u>Davis A</u>
<u>Davis A. W.</u>	<u>Davis B.</u>	<u>Davis B. A.</u>	<u>Davis B. C.</u>	<u>Davis E</u>
<u>Davis B. J.</u>	<u>Davis B. K.</u>	<u>Davis B. R.</u>	<u>Davis B. S.</u>	<u>Davis E</u>
<u>Davis B. V.</u>	<u>Davis B. W.</u>	<u>Davis C.</u>	<u>Davis C. A.</u>	<u>Davis C</u>
<u>Davis C. B.</u>	<u>Davis C. C.</u>	<u>Davis C. D.</u>	<u>Davis C. E.</u>	<u>Davis C</u>
<u>Davis C. G.</u>	<u>Davis C. H.</u>	<u>Davis C. J.</u>	<u>Davis C. Jr.</u>	<u>Davis C</u>
<u>Davis C. L.</u>	<u>Davis C. M.</u>	<u>Davis C. O.</u>	<u>Davis C. P.</u>	<u>Davis C</u>
<u>Davis C. R.</u>	<u>Davis C. S.</u>	<u>Davis C. V.</u>	<u>Davis D.</u>	<u>Davis C</u>

Next 50

ABCDEFGHIJKLMNOPQRSTUVWXYZ | ALL

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

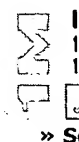
Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

 Your search matched **14** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Demonstration of a fiber optic array of three-axis magnetometers for undersea application
Bucholtz, F.; Dagenais, D.M.; Villarruel, C.A.; Kirkendall, C.K.; McVicker, J.A.; Davis, A.R.; Patrick, S.S.; Koo, K.P.; Wang, G.; Valo, H.; Eidem, E.J.; Andersen, A.; Lund, T.; Gjessing, R.; Knudsen, T.;

Magnetism, IEEE Transactions on , Volume: 31 , Issue: 6 , Nov. 1995

Pages:3194 - 3196

[\[Abstract\]](#) [\[PDF Full-Text \(312KB\)\]](#) IEEE JNL

2 Multichannel fiber-optic magnetometer system for undersea measurements
Bucholtz, F.; Villarruel, C.A.; Davis, A.R.; Kirkendall, C.K.; Dagenais, D.M.; McVicker, J.A.; Patrick, S.S.; Koo, K.P.; Gunnar Wang; Valo, H.; Lund, T.; Andersen, A.G.; Gjessing, R.; Eidem, E.J.; Knudsen, T.;

Lightwave Technology, Journal of , Volume: 13 , Issue: 7 , July 1995

Pages:1385 - 1395

[\[Abstract\]](#) [\[PDF Full-Text \(1132KB\)\]](#) IEEE JNL

3 Gain-clamped SOA with 1-11 dB variable gain based on a three-cont tunable DBR laser
Sosabowski, J.; Davies, A.R.; Penty, R.V.; White, I.H.;

Lasers and Electro-Optics Europe, 2003. CLEO/Europe. 2003 Conference on , June 2003

Pages:162

[\[Abstract\]](#) [\[PDF Full-Text \(210KB\)\]](#) IEEE CNF

4 64-element time-division multiplexed interferometric sensor array with EDFA telemetry
Kersey, A.D.; Dandridge, A.; Davis, A.R.; Kirkendall, C.K.; Marrone, M.J.; Gro D.G.;

Optical Fiber Communications, 1996. OFC '96 , 25 Feb.-1 March 1996

Pages:270 - 271

[\[Abstract\]](#) [\[PDF Full-Text \(208KB\)\]](#) IEEE CNF

5 1-to N-way phased array resonator with phase conjugate mirror

Jenkins, R.M.; Banerji, J.; Davies, A.R.;

Lasers and Electro-Optics Europe, 2000. Conference Digest. 2000 Conference on , 10-15 Sept 2000

Pages:1 pp.

[\[Abstract\]](#) [\[PDF Full-Text \(104KB\)\]](#) IEEE CNF

6 Laser Resonators with Self-Imaging Waveguides

Banerji, J.; Davies, A.R.; Jenkins, R.M.;

Lasers and Electro-optics Europe, 1996. CLEO/Europe., Conference on , 8-13 : 1996

Pages:168 - 168

[\[Abstract\]](#) [\[PDF Full-Text \(84KB\)\]](#) IEEE CNF

7 Low wavelength drift uncooled laser using tuned distributed Bragg reflectors

Davies, A.R.; Fan, S.; Williams, K.A.; Pentty, R.V.; White, I.H.;

Lasers and Electro-Optics Society, 2002. LEOS 2002. The 15th Annual Meeting of the IEEE , Volume: 2 , 10-14 Nov. 2002

Pages:861 - 862 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(222KB\)\]](#) IEEE CNF

8 Variable gain operation of a gain-clamped sampled grating laser amplifier

Davies, A.R.; Williams, K.A.; Pentty, R.V.; White, I.H.; Glick, M.; McAuley, D.;

Lasers and Electro-Optics, 2002. CLEO '02. Technical Digest. Summaries of Papers Presented at the , 19-24 May 2002

Pages:372 - 373 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(346KB\)\]](#) IEEE CNF

9 Remote Fiber Optic AC Magnetometer

Davis, A.R.; Patrick, S.S.; Dandridge, A.; Bucholtz, F.;

Optical Fiber Sensors Conference, 1992. 8th , Jan. 29-31, 1992

Pages:414 - 417

[\[Abstract\]](#) [\[PDF Full-Text \(184KB\)\]](#) IEEE CNF

10 Video compression employing algorithm using temporal blocking structures

Gregory, N.; Davies, A.R.; Darnell, M.; Boussakta, S.;

Electronics Letters , Volume: 37 , Issue: 9 , 26 April 2001

Pages:563 - 564

[\[Abstract\]](#) [\[PDF Full-Text \(272KB\)\]](#) IEEE JNL

11 Undersea performance of eight-element fibre optic magnetometer

Bucholtz, F.; Wang, G.; Kirkendall, C.K.; Villaruel, C.A.; Davis, A.R.; Dagenais,

D.M.; McVicker, J.A.; Patrick, S.S.; Koo, K.P.; Andersen, A.; Valo, H.; Gjessin, Eidem, E.J.; Knudsen, T.;
Electronics Letters ,Volume: 30 , Issue: 23 , 10 Nov. 1994
Pages:1974 - 1975

[\[Abstract\]](#) [\[PDF Full-Text \(184KB\)\]](#) IEE JNL

12 Fibre optic magnetometer system for undersea applications

Bucholtz, F.; Villarruel, C.A.; Kirkendall, C.K.; Dagenais, D.M.; McVicker, J.A.; Davis, A.R.; Patrick, S.S.; Koo, K.P.; Wathen, K.G.; Dandridge, A.; Wang, G.; Lund, T.; Valo, H.;
Electronics Letters ,Volume: 29 , Issue: 11 , 27 May 1993
Pages:1032 - 1033

[\[Abstract\]](#) [\[PDF Full-Text \(164KB\)\]](#) IEE JNL

13 Remote fibre-optic AC magnetometer

Davis, A.R.; Patrick, S.S.; Dandridge, A.; Bucholtz, F.;
Electronics Letters ,Volume: 28 , Issue: 3 , 30 Jan. 1992
Pages:271 - 273

[\[Abstract\]](#) [\[PDF Full-Text \(256KB\)\]](#) IEE JNL

14 Curve and corner extraction using the multiresolution Fourier trans

Davies, A.R.; Wilson, R.;
Image Processing and its Applications, 1992., International Conference on , 7-
Apr 1992
Pages:282 - 285

[\[Abstract\]](#) [\[PDF Full-Text \(244KB\)\]](#) IEE CNF

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

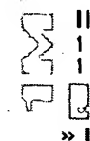
Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**
[Help](#)

- 1) Enter keywords in one or more text boxes.
- 2) Select the fields to search for each keyword.
- 3) Select search operators when using multiple keywords.
- 4) Limit the results by selecting Search Options.
- 5) Click Search. See [Search Examples](#)

 In:

 In:

 In:

Note: This function returns plural and suffixed forms of the keyword(s).

Search Options:
Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: to
Organize search results by:

 Sort by:

 In: order

 List Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

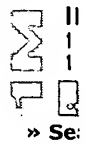
Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership | Publications/Services | Standards | Conferences | Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

 Your search matched **0** of **1121826** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

Results:
No documents matched your query.
Print Format
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

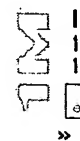
Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**[Help](#)

- 1) Enter keywords in one or more text boxes.
- 2) Select the fields to search for each keyword.
- 3) Select search operators when using multiple keywords.
- 4) Limit the results by selecting Search Options.
- 5) Click Search. See [Search Examples](#)

 In:
And
 In:
And
 In:

Note: This function returns plural and suffixed forms of the keyword(s).

Search Options:

Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: to

Organize search results by:

Sort by: In: orderList Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1121826** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.** **Print Format**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**[Help](#)

- 1) Enter keywords in one or more text boxes.
- 2) Select the fields to search for each keyword.
- 3) Select search operators when using multiple keywords.
- 4) Limit the results by selecting Search Options.
- 5) Click Search. See [Search Examples](#)

 In: And In: And In:

Note: This function returns plural and suffixed forms of the keyword(s).

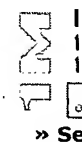
Search Options:**Select publication types:**

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:From year: to **Organize search results by:**Sort by: In: orderList Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office

» See

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1121826** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.** **Print Format**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**
[Help](#)

- 1) Enter keywords in one or more text boxes.
- 2) Select the fields to search for each keyword.
- 3) Select search operators when using multiple keywords.
- 4) Limit the results by selecting Search Options.
- 5) Click Search. See [Search Examples](#)

 In:

 In:

 In:

Note: This function returns plural and suffixed forms of the keyword(s).

Search Options:
Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: to
Organize search results by:

 Sort by:

 In: order

 List Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

 Your search matched **2** of **1121826** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Improved parallelism measurement using a laser interferometer
Konkel, B.P.; Zipter, E.C.; Kirkham, E.E.;

Industry Applications, IEEE Transactions on , Volume: 27 , Issue: 4 , July-Aug 1991

Pages:606 - 610

[\[Abstract\]](#)
[\[PDF Full-Text \(432 KB\)\]](#)
IEEE JNL
2 Calculation of uncertainty of measurement in machine vision case: a system for the calibration of dial indicators
Hemming, B.; Lehto, H.;

Instrumentation and Measurement Technology Conference, 2001. IMTC 2001. Proceedings of the 18th IEEE , Volume: 1 , 21-23 May 2001

Pages:665 - 670 vol.1

[\[Abstract\]](#)
[\[PDF Full-Text \(488 KB\)\]](#)
IEEE CNF
Print Format
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**
[Help](#)

- 1) Enter keywords in one or more text boxes.
- 2) Select the fields to search for each keyword.
- 3) Select search operators when using multiple keywords.
- 4) Limit the results by selecting Search Options.
- 5) Click Search. See [Search Examples](#)

 In:

 In:

 In:

Note: This function returns plural and suffixed forms of the keyword(s).

Search Options:

Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: to

Organize search results by:

 Sort by:

 In: order

 List Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

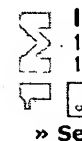
Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

 Your search matched **0** of **1121826** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

Results:
No documents matched your query.

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved